Field Effect Transistor

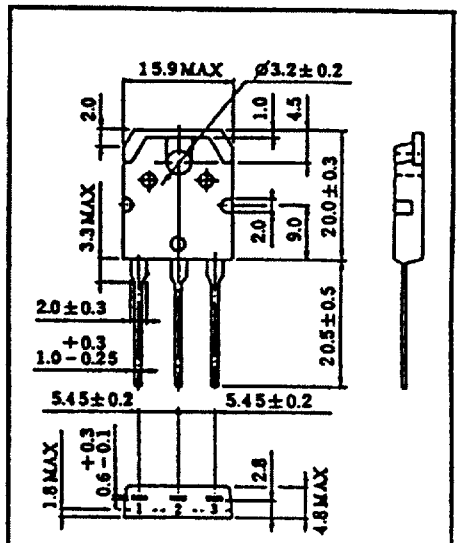
Silicon N Channel MOS Type (π-MOS II.5)

High Speed, High Current Switching Applications

Features

- Low Drain-Source ON Resistance
  - $R_{DS(ON)}$ = 1.8Ω (Typ.)
- High Forward Transfer Admittance
  - $|Y_{fs}|$ = 3.0S (Typ.)
- Low Leakage Current
  - I_{DSS} = -300μA (Max.) @ V_{DS} = 640V
- Enhancement-Mode
  - V_{th} = 1.5 ~ 3.5V @ V_{DS} = -10V, I_D = 1mA

Unit in mm



1. GATE
2. DRAIN (HEAT SINK)
3. SOURCE

JEDEC	—
EIAJ	SC-65
TOSHIBA	2-16C1B

Weight : 4.6g

Absolute Maximum Ratings (Ta = 25°C)

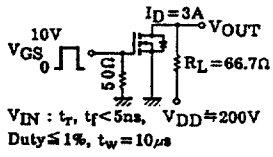
CHARACTERISTIC		SYMBOL	RATING	UNIT
Drain-Source Voltage		V_{DSS}	800	V
Drain-Gate Voltage (R_{GS} = 20kΩ)		V_{DGR}	800	V
Gate-Source Voltage		V_{GSS}	±30	V
Drain Current	DC	I_D	5	A
	Pulse	I_{DP}	15	
Drain Power Dissipation (Tc = 25°C)		P_D	125	W
Channel Temperature		T_{ch}	150	°C
Storage Temperature Range		T_{stg}	-55 ~ 150	°C

Thermal Characteristics

CHARACTERISTIC	SYMBOL	MAX.	UNIT
Thermal Resistance, Channel to Case	$R_{th(ch-c)}$	1.0	°C/W
Thermal Resistance, Channel to Ambient	$R_{th(ch-a)}$	50	°C/W

This transister is an electrostatic sensitive device. Please handle with caution.

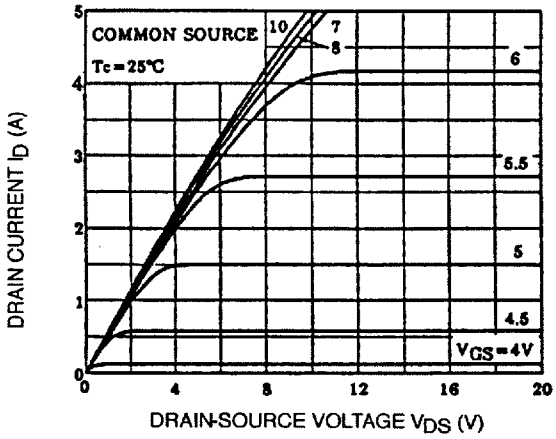
Electrical Characteristics (Ta = 25C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current		I_{GSS}	V_{GS} = ±30V, V_{DS} = 0V	–	–	±100	nA
Drain Cut-off Current		I_{DSS}	V_{DS} = 640V, V_{GS} = 0V	–	–	300	μA
Drain-Source Breakdown Voltage		$V_{(BR)\ DSS}$	I_D = 10mA, V_{GS} = 0V	800	–	–	V
Gate Threshold Voltage		V_{th}	V_{DS} = 10V, I_D = -1mA	1.5	–	3.5	V
Drain-Source ON Resistance		$R_{DS\ (ON)}$	V_{GS} = 10V, I_D = 3A	–	1.8	2.2	Ω
Forward Transfer Admittance		$\|Y_{fs}\|$	V_{DS} = 20V, I_D = 3A	1.0	3.0	–	S
Input Capacitance		C_{iss}	V_{DS} = 25V, V_{GS} = 0V, f = 1MHz	–	610	870	pF
Reverse Transfer Capacitance		C_{rss}		–	60	100	
Output Capacitance		C_{oss}		–	110	165	
Switching Time	Rise Time	t_r		–	30	60	ns
	Turn-on Time	t_{on}		–	70	140	
	Fall Time	t_f		–	35	70	
	Turn-off Time	t_{off}		–	165	330	
Total Gate Charge (Gate-Source Plus Gate-Drain)		Q_g	V_{DD} = 400V, V_{GS} = 10V, ID = -5A	–	47	94	nC
Gate-Source Charge		Q_{gs}		–	19	–	
Gate-Drain ("Miller") Charge		Q_{gd}		–	28	–	

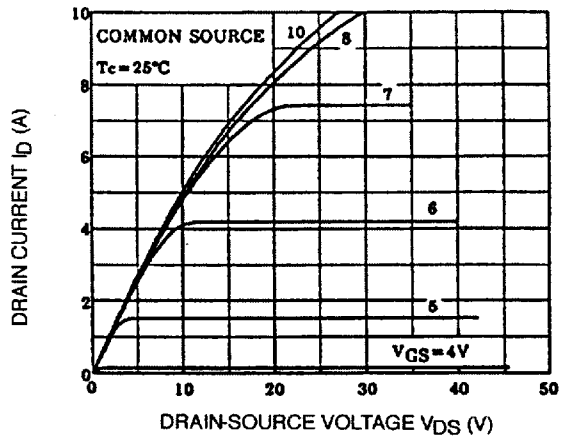
Source-Drain Diode Ratings and Characteristics (Ta = 25C)

CHARACTERISTICS	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Continuous Drain Reverse Current	I_{DR}	–	–	–	5	A
Pulse Drain Reverse Current	I_{DRP}	–	–	–	15	A
Diode Forward Voltage	V_{DSF}	I_{DR} = 5A, V_{GS} = 0V	–	–	-1.9	V
Reverse Recovery Time	t_{rr}	I_{DR} = 5A, V_{GS} = 0V, dI_{DR}/dt = 100A/μs	–	1450	–	ns
Reverse Recovered Charge	Q_{rr}		–	20	–	μC

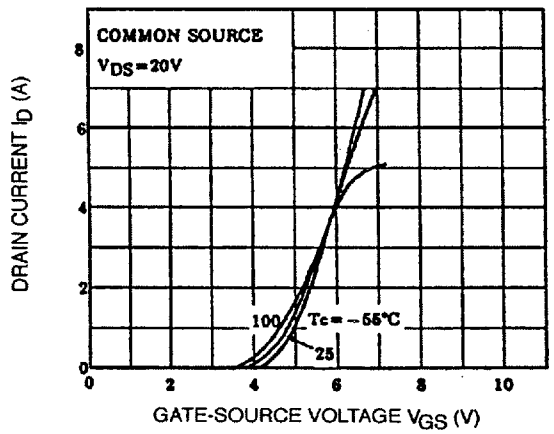
I_D - V_{DS}



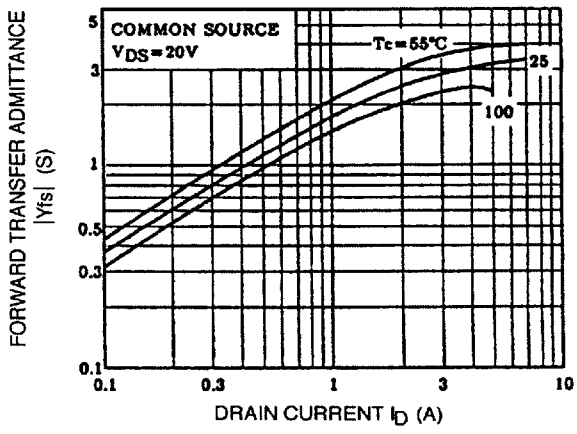
I_D - V_{DS}



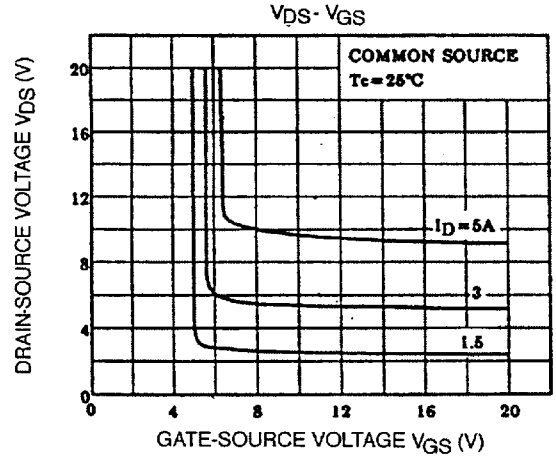
I_D - V_{GS}



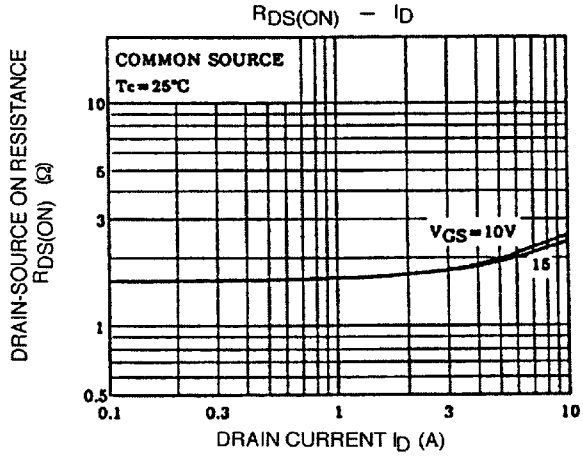
$|Y_{fs}|$ – I_D



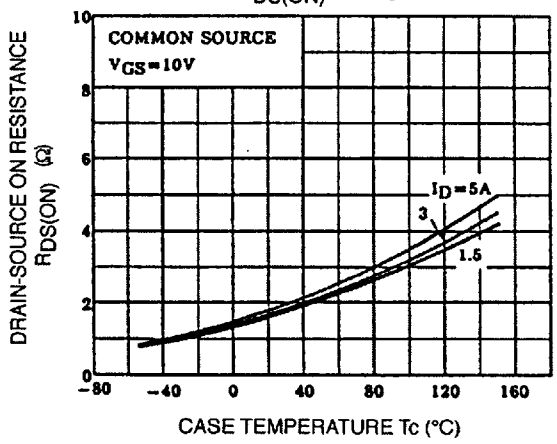
V_{DS} - V_{GS}



$R_{DS(ON)}$ – I_D

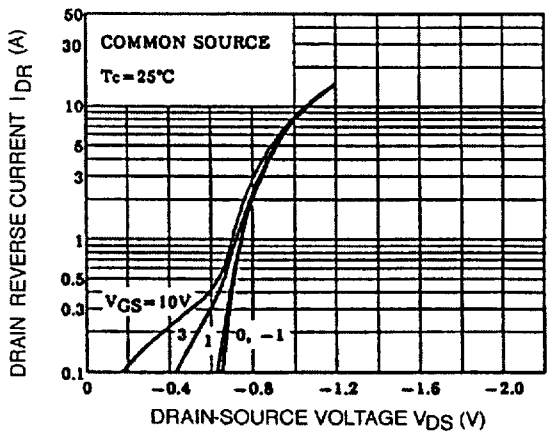


$R_{DS(ON)}$ – Tc

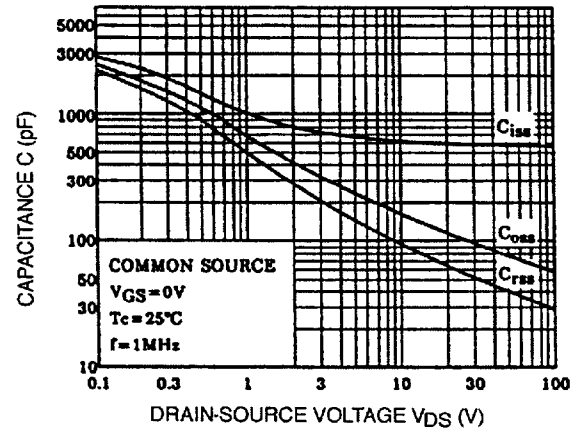


$V_{DS\ (ON)}$ – Tc

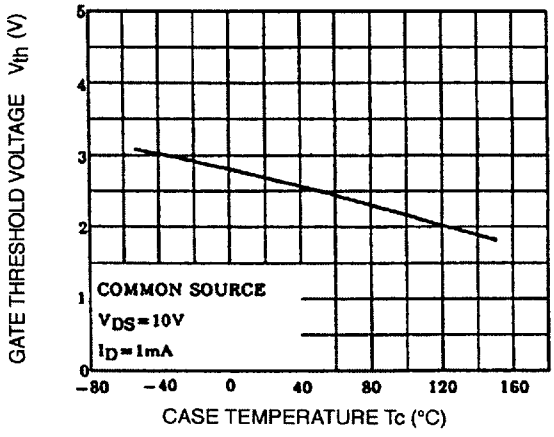
I_{DR} – V_{DS}



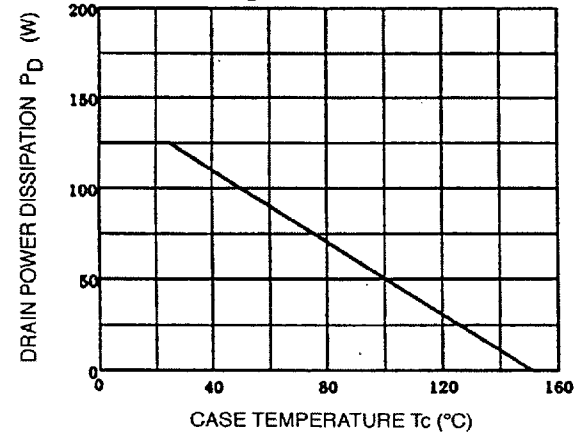
CAPACITANCE – V_{DS}



V_{th} – Tc



P_D – Tc



DYNAMIC INPUT/OUTPUT CHARACTERISTICS